MSKSEMI 美森科







T00



MOV



GDT



PIFF

SS8550

Product specification





TRANSISTOR (PNP)

FEATURES

- High Collector Current
- Complementary to SS8050

Reference News

PACKAGE OUTLINE		MARKING		
1 2	1. BASE 2. EMITTER 3.COLLECTOR	Y2		
SOT-23				

MAXIMUM RATINGS (Ta=25℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	-40	V
Vceo	Collector-Emitter Voltage	-25	V
V _{EBO}	Emitter-Base Voltage	-5	V
lc	Collector Current	-1.5	Α
Pc	Collector Power Dissipation	300	mW
R _{OJA}	Thermal Resistance From Junction To Ambient	417	°C/W
Tj	Junction Temperature	150	°C
T _{stg}	Storage Temperature	-55 ~ +150	$^{\circ}$

ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)

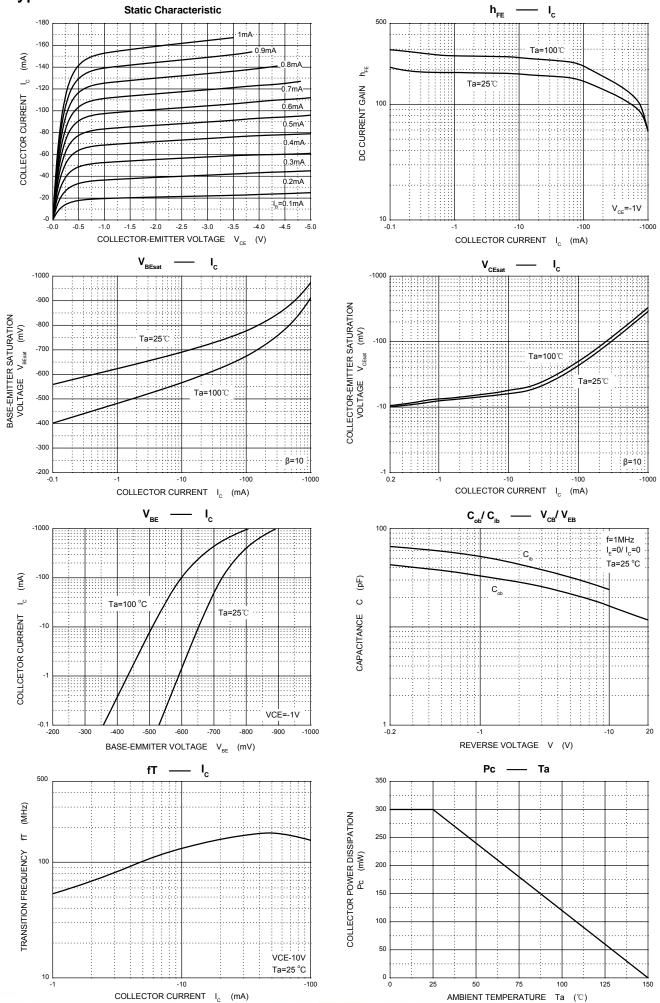
Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	l _C =-100μA, I _E =0	-40			V
Collector-emitter breakdown voltage	V _(BR) CEO	I _C =-0.1mA, I _B =0	-25			V
Emitter-base breakdown voltage	$V_{(BR)EBO}$	l _E =-100μA, l _C =0	-5			V
Collector cut-off current	Ісво	V _{CB} =-40V, I _E =0			- 100	nA
Collector cut-off current	ICEO	V _{CE} =-20V, I _B =0			- 100	nA
Emitter cut-off current	I _{EBO}	V _{EB} =-5V, I _C =0			- 100	nA
DC current gain	h _{FE(1)}	V _{CE} =- 1V, I _C =- 100mA	120		400	
Do current gam	h _{FE(2)}	V _{CE} =-1V, I _C =-800mA	40			
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =-800mA, I _B =-80mA			-0.5	V
Base-emitter saturation voltage	V _{BE(sat)}	I _C =-800mA, I _B =-80mA			-1.2	V
Base-emitter voltage	V_{BE}	V _{CE} =-1V, I _C =-10mA			-1	V
Transition frequency	f⊤	V _{CE} =- 10V,I _C =-50mA , f=30MHz	100			MHz
Collector output capacitance	Cob	V _{CB} =- 10V, I _E =0, f=1MHz			20	pF

CLASSIFICATION OF hfe(1)

RANK	L	Н	J
RANGE	120 –200	200 –350	300 –400

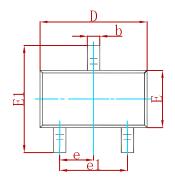


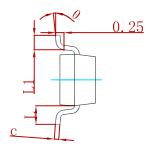
Typical Characterisitics

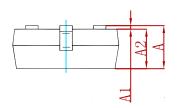




PACKAGE MECHANICAL DATA

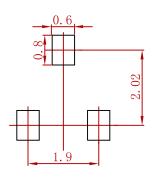






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Зупроі	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022	REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SS8550	SOT-23	3000



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